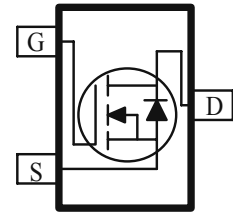
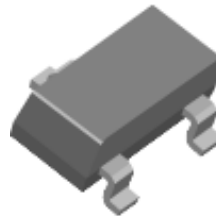


These miniature surface mount MOSFETs utilize a high cell density trench process to provide low  $r_{DS(on)}$  and to ensure minimal power loss and heat dissipation. Typical applications are DC-DC converters and power management in portable and battery-powered products such as computers, printers, PCMCIA cards, cellular and cordless telephones.

<b>PRODUCT SUMMARY</b>		
<b>V<sub>DS</sub> (V)</b>	<b>r<sub>DS(on)</sub> (Ω)</b>	<b>I<sub>D</sub> (A)</b>
30	0.058 @ V <sub>GS</sub> = 10 V	2.0
	0.082 @ V <sub>GS</sub> = 4.5V	1.7

- Low  $r_{DS(on)}$  provides higher efficiency and extends battery life
- Low thermal impedance copper leadframe SC70-3 saves board space
- Fast switching speed
- High performance trench technology



<b>ABSOLUTE MAXIMUM RATINGS (T<sub>A</sub> = 25 °C UNLESS OTHERWISE NOTED)</b>				
<b>Parameter</b>		<b>Symbol</b>	<b>Maximum</b>	<b>Units</b>
Drain-Source Voltage		V <sub>DS</sub>	30	V
Gate-Source Voltage		V <sub>GS</sub>	±20	
Continuous Drain Current <sup>a</sup>	T <sub>A</sub> =25°C	I <sub>D</sub>	2.0	A
	T <sub>A</sub> =70°C		1.7	
Pulsed Drain Current <sup>b</sup>		I <sub>DM</sub>	±20	
Continuous Source Current (Diode Conduction) <sup>a</sup>		I <sub>S</sub>	1.6	A
Power Dissipation <sup>a</sup>	T <sub>A</sub> =25°C	P <sub>D</sub>	0.34	W
	T <sub>A</sub> =70°C		0.22	
Operating Junction and Storage Temperature Range		T <sub>J</sub> , T <sub>stg</sub>	-55 to 150	°C

<b>THERMAL RESISTANCE RATINGS</b>				
<b>Parameter</b>		<b>Symbol</b>	<b>Maximum</b>	<b>Units</b>
Maximum Junction-to-Ambient <sup>a</sup>	t ≤ 5 sec	R <sub>THJA</sub>	100	°C/W
	Steady-State		166	

Notes

- Surface Mounted on 1" x 1" FR4 Board.
- Pulse width limited by maximum junction temperature



SPECIFICATIONS (T <sub>A</sub> = 25°C UNLESS OTHERWISE NOTED)						
Parameter	Symbol	Test Conditions	Limits			Unit
			Min	Typ	Max	
<b>Static</b>						
Gate-Threshold Voltage	V <sub>GS(th)</sub>	V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> = 250 μA	1			V
Gate-Body Leakage	I <sub>GSS</sub>	V <sub>DS</sub> = 0 V, V <sub>GS</sub> = ±20 V			±100	nA
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>DS</sub> = 24 V, V <sub>GS</sub> = 0 V			1	μA
		V <sub>DS</sub> = 24 V, V <sub>GS</sub> = 0 V, T <sub>J</sub> = 55°C			10	
On-State Drain Current <sup>A</sup>	I <sub>D(on)</sub>	V <sub>DS</sub> = 5 V, V <sub>GS</sub> = 10 V	10			A
Drain-Source On-Resistance <sup>A</sup>	r <sub>DS(on)</sub>	V <sub>GS</sub> = 10 V, I <sub>D</sub> = 2.0 A			58	mΩ
		V <sub>GS</sub> = 4.5 V, I <sub>D</sub> = 1.7 A			82	
Forward Transconductance <sup>A</sup>	g <sub>fs</sub>	V <sub>DS</sub> = 10 V, I <sub>D</sub> = 2.0 A		11.3		S
Diode Forward Voltage	V <sub>SD</sub>	I <sub>S</sub> = 1.6 A, V <sub>GS</sub> = 0 V		0.75		V
<b>Dynamic<sup>b</sup></b>						
Total Gate Charge	Q <sub>g</sub>	V <sub>DS</sub> = 10 V, V <sub>GS</sub> = 5 V, I <sub>D</sub> = 2.0 A		7.5		nC
Gate-Source Charge	Q <sub>gs</sub>			0.6		
Gate-Drain Charge	Q <sub>gd</sub>			1.0		
Turn-On Delay Time	t <sub>d(on)</sub>	V <sub>DD</sub> = 10 V, R <sub>L</sub> = 15 Ω, I <sub>D</sub> = 1 A, V <sub>GEN</sub> = 4.5 V		8		ns
Rise Time	t <sub>r</sub>			24		
Turn-Off Delay Time	t <sub>d(off)</sub>			35		
Fall-Time	t <sub>f</sub>			10		

Notes

- a. Pulse test: PW ≤ 300μs duty cycle ≤ 2%.
- b. Guaranteed by design, not subject to production testing.